Silicon N-channel IGBT 4500V F version

FEATURES

* Soft switching behavior, low switching loss & low conduction loss :

Soft low-injection punch-through

Advanced Trench High conductivity IGBT.

- * Low driving power due to low input capacitance with trench MOS gate.
- * Low noise recovery: Ultra soft fast recovery diode.
- * High Current rate Package.
- * Low Rth(j-c) & low stray inductance.
- * RoHS

ABSOLUTE MAXIMUM RATINGS (T_C=25°C)

Item		Symbol	Unit	MBN1500FH45F
Collector Emitter Voltage		V _{CES}	V	4,500
Gate Emitter Voltage		V_{GES}	V	±20
Collector Current DC		Ic	Λ	1,500
Collector Current	1ms	I _{CRM}	— A	3,000
Forward Current	DC	l _F	Λ	1,500
Forward Current	1ms	I _{FRM}	A	3,000
Junction Temperature	·	T _{vj op}	°C	-50 ~ + 150
Storage Temperature		T _{stg}	°C	-50 ~ + 150
Isolation Voltage		V _{ISO}	V _{RMS}	10,200(AC 1 minute)
Sorow Torque	Terminals (M4/M8)	-	N·m	2/10 (1)
Screw Torque	Mounting (M6)	-	IN-III	6 (2)

Notes: (1) Recommended Value 1.8±0.2/9±1N⋅m

(2) Recommended Value 5.5±0.5N·m

ELECTRICAL CHARACTERISTICS

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions
Collector Emitter Cut-Off Current	lana	mΑ	-	-	6	V _{CE} =4,500V, V _{GE} =0V, T _{vj} =25°C
	I _{CES}	шл	-	60	180	V _{CE} =4,500V, V _{GE} =0V, T _{vj} =150°C
Gate Emitter Leakage Current	I _{GES}	nΑ	-500	-	+500	$V_{GE}=\pm 20V, V_{CE}=0V, T_{vj}=25^{\circ}C$
Collector Emitter Saturation Voltage	V _{CEsat}	V	-	3.0	3.4	I _C =1,500A, V _{GE} =15V, T _{vj} =150°C
Gate Emitter Threshold Voltage	V _{GE(th)}	V	6.0	6.5	7.0	V _{CE} =10V, I _C =1,500mA, T _{vj} =25°C
Input Capacitance	Cies	nF	-	83	-	V _{CE} =10V, V _{GE} =0V, f=100kHz, T _{vj} =25°C
Internal Gate Resistance	R _{G(int)}	Ω	-	2.6	-	V _{CE} =10V, V _{GE} =0V, f=100kHz, T _{vj} =25°C
Turn On Delay Time	t _{d(on)}		-	0.5	-	V _{CC} =2,800V, I _C =1,500A
Rise Time	t _r		-	0.25	-	L _S =165nH
Turn Off Delay Time	t _{d(off)}	μS	-	2.8	-	$R_{G}(\text{on/off})=3.3/3.3\Omega$ (3)
Fall Time	t _f			2.1	-	$V_{GE}=\pm 15V, T_{vj}=150^{\circ}C$
Forward Voltage Drop	V_{F}	V	-	2.8	3.2	I _F =1,500A, V _{GE} =0V, T _{vj} =150°C
Reverse Recovery Time	t _{rr}	μS	-	1.3	_	V _{CC} =2,800V, I _F =1,500A, L _S =165nH
Reverse Recovery Time	Lrr				_	T _{vj} =150°C
Turn On Loss	Eon	J/P	-	4.8	-	V _{CC} =2,800V, I _C =1,500A, L _S =165nH
Turn Off Loss	E _{off}	J/P	-	8.0	-	$R_{G}(\text{on/off})=3.3/3.3\Omega$ (3)
Reverse Recovery Loss	Err	J/P	-	6.3	-	$V_{GE}=\pm 15V, T_{vj}=150^{\circ}C$
Short Circuit Pulse Width		0	10	_		V _{CC} =3,000V, Ls=165nH
Short Circuit Puise Width	t _{sc}	μS	10	-	_	$R_G(on/off)=3.3/33\Omega, V_{GE}=\pm 15V, T_{vi}=150^{\circ}C$
Partial discharge extinction voltage	Ve	V_{RMS}	3,500	-	-	f=50Hz, Q _{PD} ≤10pC(acc. to IEC 61287)
Stray inductance module	L _{SCE}	nΗ	-	10	-	
Thermal Impedance IGBT	R _{th(j-c)}	K/W	-	-	0.0085	Junction to case
FWD	R _{th(j-c)}	r\/vv	-	-	0.0115	
Contact Thormal Impedance		K/W		0.005		Case to fin (λ grease = 1W/(m·K)
Contact Thermal Impedance	R _{th(c-f)}	r\/vv	-	0.005	-	heat-sink flatness ≤ 50μm)

Notes: (3) R_G value is a test condition value for evaluation, not recommended value. Please, determine the suitable R_G value by measuring switching behaviors.

^{*} Please contact our representatives at order.

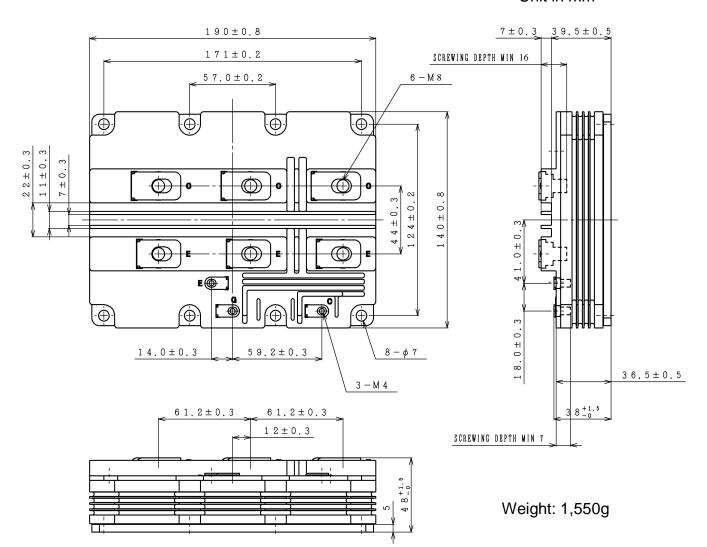
^{*} For improvement, specifications are subject to change without notice.

^{*} For actual application, please confirm this spec sheet is the newest revision.

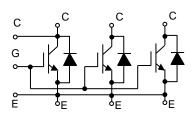
^{*} ELECTRICAL CHARACTERISTIC items shown in above table are according to IEC 60747-2 and IEC 60747-9.

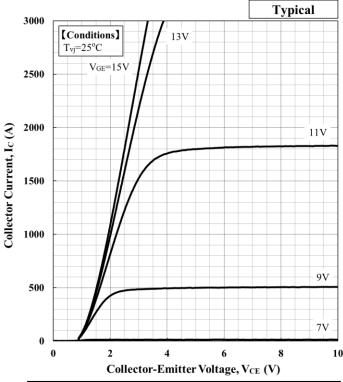
OUTLINE DRAWING

Unit in mm



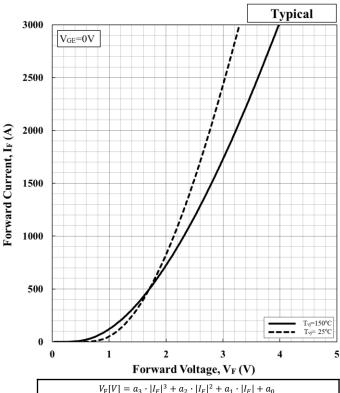
CIRCUIT DIAGRAM





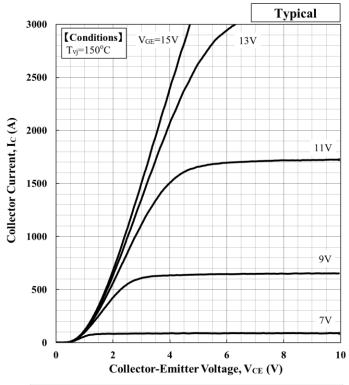
$V_{CE}(sat)[V] = a_3 \cdot I_c ^3 + a_2 \cdot I_c ^2 + a_1 \cdot I_c + a_0$							
Temp.[°C]	$V_{GE}[V]$	a_3	a_2	a_1	a_0		
25	15	3.92E-11	-2.39E-07	1.14E-03	9.98E-01		

Collector Current vs. Collector Emitter Voltage



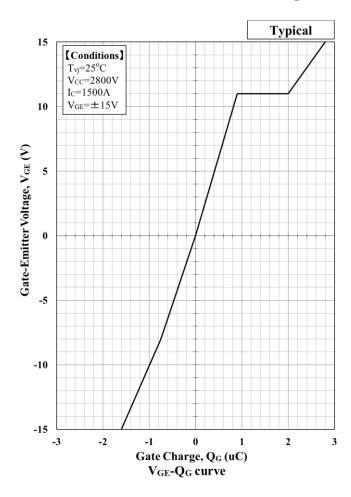
$V_{F}[V] = a_{3} \cdot I_{F} ^{3} + a_{2} \cdot I_{F} ^{2} + a_{1} \cdot I_{F} + a_{0}$							
Temp.[°C]	a_0						
25	5.30E-11	-3.63E-07	1.35E-03	1.10E+00			
150	6.59E-11	-4.62E-07	1.83E-03	8.75E-01			

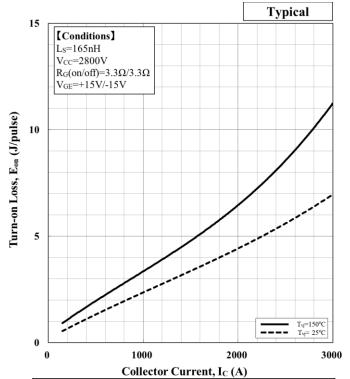
Forward Voltage of free-wheeling diode



$V_{\text{CE}}(sat)[V] = a_3 \cdot I_c ^3 + a_2 \cdot I_c ^2 + a_1 \cdot I_c + a_0$							
Temp.[°C]	V _{GE} [V]	a_3	a_2	a_1	a_0		
150	15	6.37E-11	-3.80E-07	1.84E-03	8.92E-01		

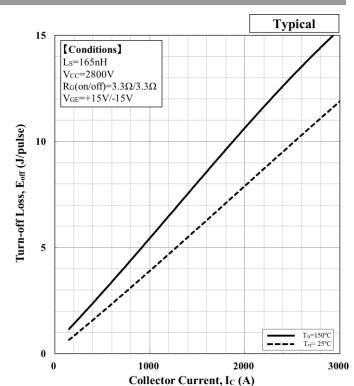
Collector Current vs. Collector Emitter Voltage





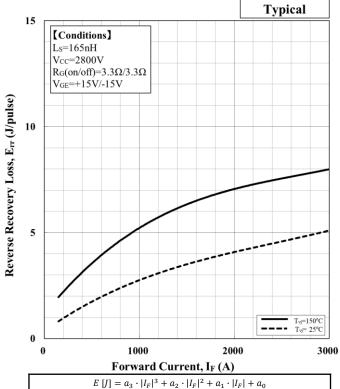
$E\left[J\right] = a_3 \cdot I_c ^3 + a_2 \cdot I_c ^2 + a_1 \cdot I_c + a_0$							
Temp.[°C]	a_3	a_2 a_1		a_0			
25	9.68E-11	-3.41E-07	2.41E-03	1.90E-01			
150	2.47E-10	-6.38E-07	3.30E-03	4.38E-01			

Turn-on loss vs. Collector current



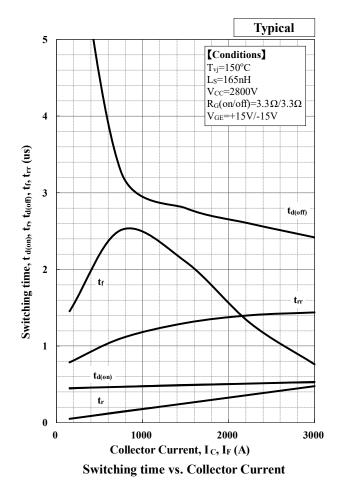
$E[J] = a_3 \cdot I_c ^3 + a_2 \cdot I_c ^2 + a_1 \cdot I_c + a_0$							
Temp.[$^{\circ}$ C] a_3 a_2 a_1 a_0							
25	-3.59E-11	2.07E-07	3.63E-03	1.02E-01			
150	-1.26E-10	4.82E-07	4.63E-03	4.59E-01			

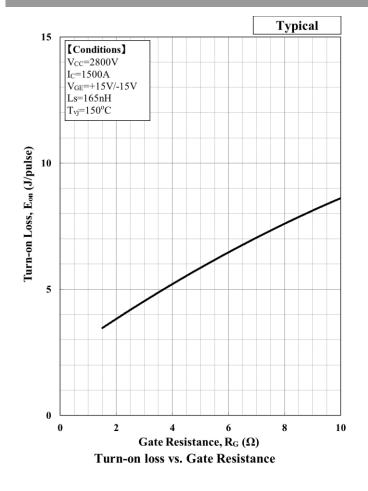
Turn-off loss vs. Collector current

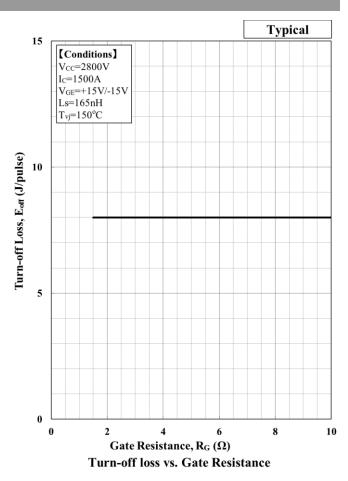


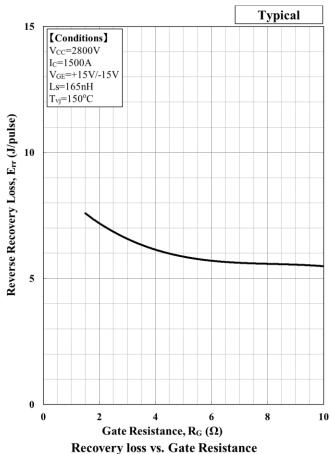
$E[J] = a_3 \cdot I_F ^3 + a_2 \cdot I_F ^2 + a_1 \cdot I_F + a_0$							
Temp.[°C]	a_1	a_0					
25	1.26E-10	-9.11E-07	3.18E-03	3.56E-01			
150	2.20E-10	-1.77E-06	5.61E-03	1.15E+00			

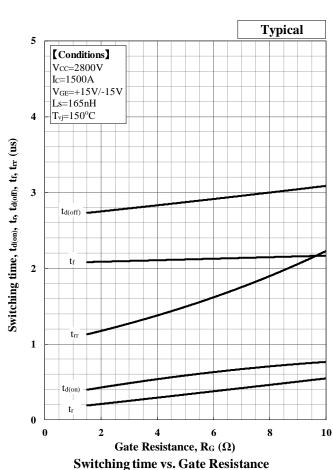
Recovery loss vs. Forward current

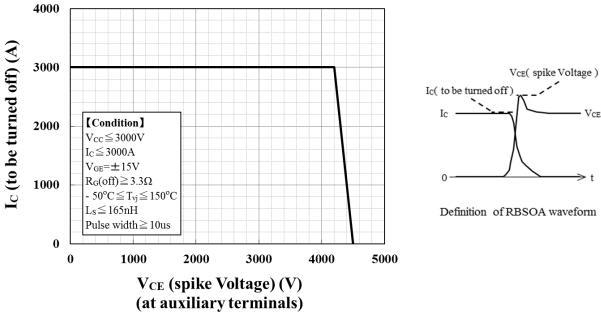




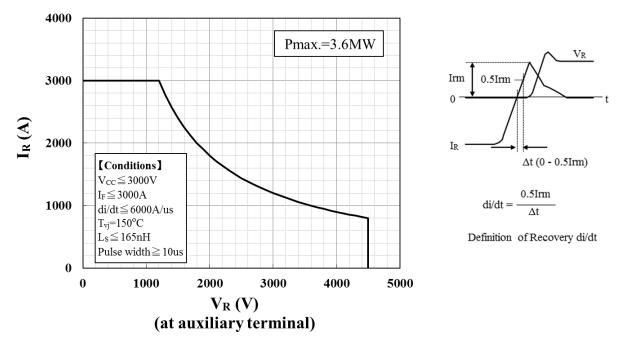




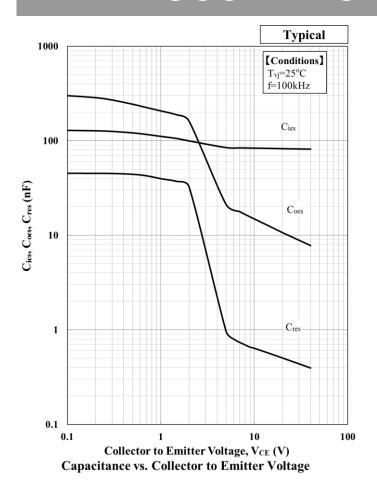


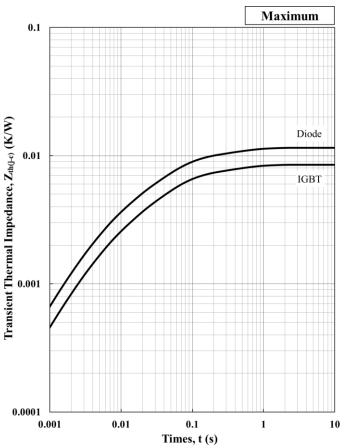


Reverse bias safe operation area (RBSOA)



Reverse recovery safe operation area(RRSOA)





Transient Thermal Impedance Curve

Foster model lumped circuit constant

n	1	2	3	4	Unit
R th, IGBT [n]	1.76E-03	4.75E-03	1.63E-03	3.62E-04	[K/W]
C th, IGBT [n]	2.26E+02	9.79E+00	4.18E+00	6.17E+00	[J/K]
R th, Diode [n]	2.34E-03	6.25E-03	2.33E-03	5.78E-04	[K/W]
C th, Diode [n]	1.70E+02	7.43E+00	2.93E+00	3.86E+00	[J/K]

Cauer model lumped circuit constant

n	1	2	3	4	Unit
R th, IGBT [n]	2.35E-03	1.74E-03	3.11E-03	1.30E-03	[K/W]
C th, IGBT [n]	1.97E+00	3.35E+00	8.89E+00	2.90E+02	[J/K]
R th, Diode [n]	3.25E-03	2.39E-03	4.14E-03	1.73E-03	[K/W]
C th, Diode [n]	1.35E+00	2.49E+00	6.92E+00	2.18E+02	[J/K]

Minebea POWER SEMICONDUCTORS

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